
Measurement of quartz crystal unit parameters - Part 8: Test fixture for surface mounted quartz crystal units (IEC 60444-8:2003)

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EUROPEAN STANDARD

EN 60444-8

NORME EUROPÉENNE

EUROPÄISCHE NORM

October 2003

ICS 31.140

English version

**Measurement of quartz crystal unit parameters
Part 8: Test fixture for surface mounted quartz crystal units
(IEC 60444-8:2003)**

Mesure des paramètres
des résonateurs à quartz
Partie 8: Dispositif d'essai
pour les résonateurs à quartz
montés en surface
(CEI 60444-8:2003)

Messung von Schwingquarz-Parametern
Teil 8: Prüfaufbau für oberflächen-
montierbare Schwingquarze
(IEC 60444-8:2003)

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This European Standard was approved by CENELEC on 2003-10-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Lithuania, Luxembourg, Malta, Netherlands, Norway, Portugal, Slovakia, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 49/599/FDIS, future edition 1 of IEC 60444-8, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60444-8 on 2003-10-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2004-07-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2006-10-01

Annexes designated "normative" are part of the body of the standard.
In this standard, annex ZA is normative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60444-8:2003 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60444-4

NOTE Harmonized as EN 60444-4:1997 (not modified)

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60444-1	1986	Measurement of quartz crystal unit parameters by zero phase technique in a pi-network Part 1: Basic method for the measurement of resonance frequency and resonance resistance of quartz crystal units by zero phase technique in a pi-network	EN 60444-1	1997
IEC 60444-2	1980	Part 2: Phase offset method for measurement of motional capacitance of quartz crystal units	EN 60444-2	1997
IEC 60444-5	1995	Part 5: Methods for the determination of equivalent electrical parameters using automatic network analyzer techniques and error correction	EN 60444-5	1997
IEC 61240	1994	Piezoelectric devices - Preparation of outline drawings of surface-mounted devices (SMD) for frequency control and selection - General rules	EN 61240	1997

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60444-8

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First edition
2003-07

**Mesure des paramètres des résonateurs
à quartz –**

**Partie 8:
Dispositif d'essai pour les résonateurs
à quartz montés en surface**

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**Measurement of quartz crystal unit
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**Part 8:
Test fixture for surface mounted
quartz crystal units**

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Commission Electrotechnique Internationale
International Electrotechnical Commission
Международная Электротехническая Комиссия

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MEASUREMENT OF QUARTZ CRYSTAL UNIT PARAMETERS –**Part 8: Test fixture for surface mounted quartz crystal units**

FOREWORD

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International Standard IEC 60444-8 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This International Standard cancels and replaces IEC/PAS 62277 published in 2001, of which it constitutes a technical revision.

This bilingual version (2003-10) replaces the English version.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/599/FDIS	49/611/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.